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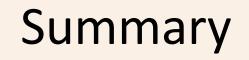


Burn-in & Test Strategies Workshop

www.bitsworkshop.org

March 6-9, 2016

Bits 2016



Learn...

Tutorial, Distinguished Speaker, Keynote, 30 Papers, 5 Posters
> 800 PowerPoint slides

Explore...

- BiTS EXPO: 47 Exhibitors (49 Booths)

Share...

– Meals, Networking, Social Event

What's NOW & NEXT in Test & Burn-in of Packaged ICs



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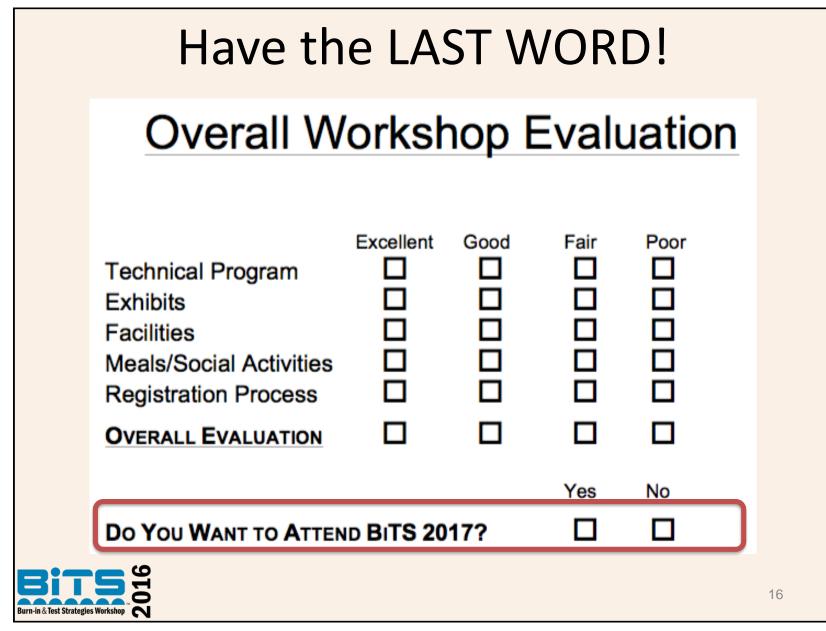


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- Professional 200
 - 34% International
 - Japan 24, Europe 18, Korea 13
- Total 359







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Current Workshop

- Call For Papers
- EXPO & Sponsorships
- Advance/Final Program
- Registration Information & Forms; Register On-line
- Author Information
- Hotel Information/Travel

<u>Features</u>

- Committee Members
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- Links to Other Websites
- 'Press' About BiTS
- Archive of past BiTS
- Search BiTS Feature

Plus Premium Archive...



Bits 2016

BiTS Premium Archive

- Multimedia
 - Audio with synchronized slides & pointer
 - BiTS 2013, BiTS 2014, BiTS 2015
 - BiTS Shanghai 2015
 - BiTS 2016 posted shortly after BiTS
- Additional content
 - Tutorials
- Subscription Model
 - BiTS 2016 Professional Attendees Subscription for One Year
 - Subscriber Nominal Fee
 - Applied to BiTS 2017 Registration

<u>bitsworkshop.org/premium</u>



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March 5-8, 2017 • Mesa, Arizona

Presentations • Posters • Tutorial

Share your latest work and advancements as an **AUTHOR**! Your presentation or poster will be part of a stimulating and comprehensive program. Explore a demanding topic as a **TUTORIAL INSTRUCTOR**. Share your expertise with participants eager to build their leading edge skills. Presentation, Poster & Tutorial proposals addressing a broad range of burn-in and test subjects are welcome, including, but not limited to:

- Socketing/Contacting of Contemporary and Advanced Packaging Technologies
- PCBs, Materials, Handlers, Contact
- Technologies, Burn-in Tooling
- Modeling, Characterization & Analysis
- Process & Operational Challenges
- WLCSP Test for KGD or Final Test
- MEMS and Non-Electrical Stimuli Test

BiTS EXPO 2017 & Sponsors

The EVENT for exhibiting your company's products & services. Showcase and promote what is **Now & Next!**

Don't miss out! See the registration desk to sign up now at the early-bird discount rate. **BiTS EXPO** is sure to sell out!

For more information about BiTS 2017 please contact the BITS Office <u>bitsinfo@bitsworkshop.org</u>



BiTS 2016 Early Bird Abstracts

Presenter	Company	
Paul Ruo	Aries Electronics	
Larre Nelson	Kita USA	
James Tong	Texas Instruments	
Mike Gedeon	Materion	
Jack Mumbo	Intel	
Makoto Kondo	OMRON	
Gert Hohenwarter	GateWave Northern, Inc.	
Brad Emberger	Advantest	



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CCT Plastics	A24
Chip Shine, Inc.	A38
CMR Summit	A9
Cohu	A3
DuPont Vespel	A36
E-TEC Interconnect AG	A6
E. Jordan Brookes	A30
ELES Semiconductor	A7
Enplas Tech Solutions, Inc.	A44
Ensinger Inc.	A50
EXATRON	A13
HSIO Technologies	A14
Incal Technology, Inc.	A26
INNO Global	A16
Integrated Test Corp	A37
intest Corporation	A32
ISC Co., Ltd.	A43
IWIN Co., Ltd.	A11
J2M Test Solutions	A4
Johnstech International	A10
Kita USA, Inc.	A18
LEENO	A10
Materion Performance	A49
MCS	A8
Micro Control Company	A0 A5
MJC Electronics Corp.	A39
and the second	A41, A42
Modus Test, LLC	
Phoenix Test Arrays	A46
Plastronics	A48
Qualmax, Inc.	A51
R&D Altanova	A1
Rika Denshi America, Inc.	A23
SemiconductorTest	A22
Sensata Technologies	A34, A35
Smiths Connectors	A40
Sun Electric Heater	A2
SV TCL-An SV Probe	A20
Test Spectrum	A29
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TSE	A12
Twin Solution Technologies	A27
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Augura	

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- Best Poster
- Best Data Presented
- Most Inspirational Presentation
- Best Presentation, Tutorial in Nature
- Attendee Choice
- ... and ...



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